



#9A/4-26-03  
V. Jone

PATENT  
81674-271623

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

J. HALBERT et al.

Serial No: 09/664,910

Filed: September 18, 2000

For: MEMORY MODULE AND MEMORY  
COMPONENT BUILT-IN SELF TEST



Art Unit: 2133  
Examiner: D.B. GANDHI

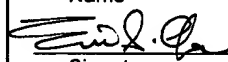
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AMENDMENT

Assistant Commissioner for Patents  
Washington, D.C. 20231

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Technology Center 2100

Dear Sir:

In response to the Office Action dated February 13, 2003 in connection with the above-identified application, please enter and consider the following amendment and remarks.

IN THE CLAIMS:

Please amend claims 1, 9, 16, 24, 31, 39, and 48 as follows:

- ai 
1. (Amended) A memory component with built-in self test, comprising:  
an input/output interface having a loopback;